

Serial No.: 10/788,545

IN THE SPECIFICATION:

Please amend the specification as follows:

Please replace the Abstract beginning at page 30, line 3, with the following amended Abstract:

-- A test switching circuit for a high speed data interface is disclosed. Test switching circuit for a high speed data interface of an integrated circuit ~~comprising~~ including switching transistors which switch in a test mode a termination resistor output stage of a data transmission signal path to a termination resistor input stage of a data reception signal path to form an internal feedback test loop within said integrated circuit. --